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Supporting information for article:

**Upgrade of the small-angle neutron scattering diffractometer
SANS-J at JRR-3**

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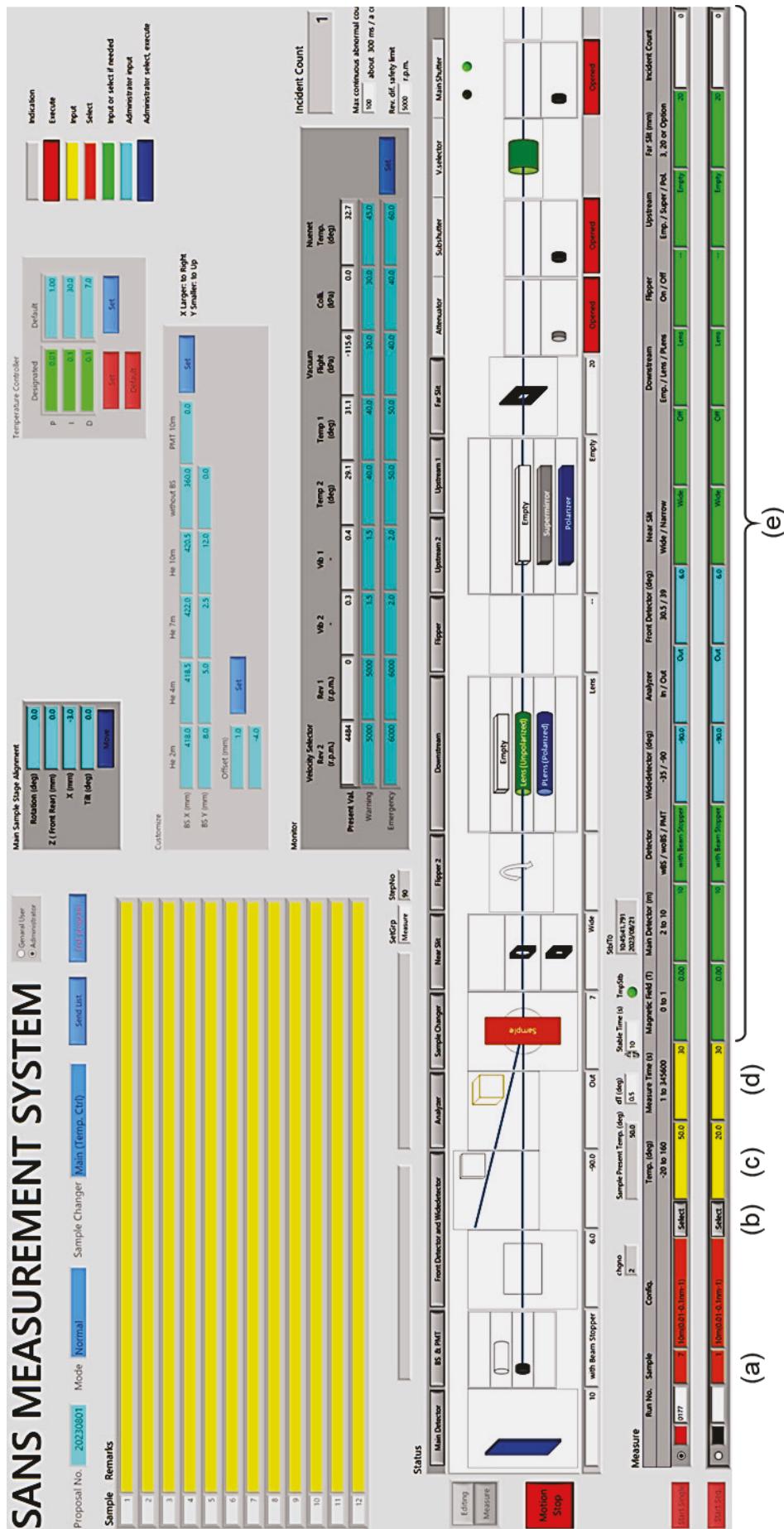


Figure S1 The display screen of measurement system. General operation procedure using tables in the lower part is as follows: (a) choose a sample in a sample changer; (b) select the standard layout from the pop-up selection list that appears by clicking the select button; (c) set temperature; (d) input measurement time; (e) customize each device layout if needed. Block diagram in the middle part shows the status of the device layout with the path of direct neutron beam (blue line). Only administrators control parameters in the cyan boxes for fundamental beam alignment.